



Metrology for Industry4.0 & IoT

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IMPORTANT DATES

JANUARY 31, 2025

SPECIAL SESSION PROPOSAL SUBMISSION DEADLINE

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EXTENDED ABSTRACT SUBMISSION DEADLINE

APRIL 7, 2025

EXTENDED ABSTRACT NOTIFICATION

APRIL 28, 2025

FINAL PAPER SUBMISSION DEADLINE



The Fourth Industrial Revolution represents a fundamental change in the way we live, work, and relate to one another. It is a new chapter in human development, enabled by technology advances that are commensurate with those of the first, second, and third industrial revolutions. The speed, breadth, and depth of this revolution are forcing us to

The 8th edition of IEEE MetroInd4.0&IoT aims to discuss the contributions both of the metrology for the development of Industry 4.0 and IoT and the new opportunities offered by Industry 4.0 and IoT for the development of new measurement methods and instruments.

Topics for IEEE MetroInd4.0&IoT 2025 include

rethink how countries should develop and how organizations create value.

- · Industrial sensors;
- · Virtual sensors, sensor interfacing;
- · Wireless sensor networks and IoT;
- · Sensors Data Management;
- · Measurement applications based on IoT;
- · IoT enabled sensors and measurement systems;
- Industrial IoT and Factory of Things;
- · Wearables and Body Sensor Networks;
- · Localization Technologies.







In addition to regular papers, many initiatives and opportunities such as special sessions, exhibits, tutorials, demos, student contests, journal papers, and others are planned to enhance your experience with the conference, and will make IEEE MetroInd4.0&IoT 2025 a vibrant event to meet with people in instrumentation and measurement for Industry4.0 and IoT applications. Papers that are accepted and presented will be submitted for inclusion in the IEEE Xplore Digital Library.